

Notice of References Cited		Application/Control No. 10/723,389	Applicant(s)/Patent Under Reexamination VEARIEL ET AL.	
		Examiner Dimple N. Bodawala	Art Unit 1722	Page 1 of 1

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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